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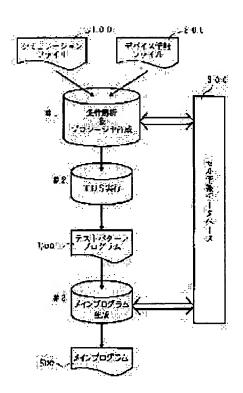
NAKAICHI YUKA

(54) TEST PROGRAM GENERATING SYSTEM

(57)Abstract:

PROBLEM TO BE SOLVED: To provide a test program generating system which achieves a reduction in the time required to generate a test program, the enhancement of circuit verification accuracy by the generated test program, and uniformity in the degree of perfection of the test program.

SOLUTION: Information stored in a simulation file 100, a device information file 200, and a cell information database 300 is processed by software to generate the procedure necessary for executing the existing software for generating a test pattern program. The existing software is executed by the generated procedure to generate a test pattern program 400. Then the generated test pattern program 400 and the information stored in the device information file 200 and the cell information database 300 are processed by the software to generate a main program 500.



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